

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Unit	
[MOSFET]				
V_{DSS}	Drain-Source Voltage	-20	V	
V_{GSS}	Gate-Source Voltage	± 10		
I_D^*	Continuous Drain Current	$V_{GS} = -4.5\text{V}$	A	
I_{DM}^*	300 μs Pulsed Drain Current			-9
I_S^*	Diode Continuous Forward Current	-1.4	A	
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$	
T_{STG}	Storage Temperature Range	-55 to 150		
P_D^*	Maximum Power Dissipation	$T_A = 25^\circ\text{C}$	1.13	W
		$T_A = 100^\circ\text{C}$	0.45	
$R_{\theta JA}^*$	Thermal Resistance-Junction to Ambient	110	$^\circ\text{C}/\text{W}$	
[SBD]				
V_{RRM}	Repetitive Peak Reverse Voltage	20	V	
V_R	DC Blocking Voltage	20	V	
I_F	Average Rectified Forward Current	Steady State	1	A
		t 5 s	2	A
$R_{\theta JA}^*$	Thermal Resistance-Junction to Ambient	Steady State	130	$^\circ\text{C}/\text{W}$
		t 5 s	100	$^\circ\text{C}/\text{W}$

Note : *Surface Mounted on 1in² pad area, t \leq 5sec.

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	APM2805QA			Unit
			Min.	Typ.	Max.	
[MOSFET]						
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}, I_{DS} = -250\mu\text{A}$	-20	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16\text{V}, V_{GS} = 0\text{V}$ $T_J = 85^\circ\text{C}$	-	-	-1	μA
			-	-	-30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{DS} = -250\mu\text{A}$	-0.45	-0.7	-1	V
I_{GSS}	Gate Leakage Current	$V_{GS} = \pm 10\text{V}, V_{DS} = 0\text{V}$	-	-	± 10	μA
$R_{DS(ON)}^a$	Drain-Source On-state Resistance	$V_{GS} = -4.5\text{V}, I_{DS} = -2.6\text{A}$	-	85	110	m Ω
		$V_{GS} = -2.5\text{V}, I_{DS} = -2\text{A}$	-	120	160	

Electrical Characteristics (Cont.) ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	APM2805QA			Unit
			Min.	Typ.	Max.	
[MOSFET]						
Diode Characteristics						
V_{SD}^a	Diode Forward Voltage	$I_{SD}=-1.4\text{A}, V_{GS}=0\text{V}$	-	-0.7	-1.3	V
t_{rr}	Reverse Recovery Time	$I_{DS}=-2.6\text{A}, di_{SD}/dt=100\text{A}/\mu\text{s}$	-	13.5	-	ns
Q_{rr}	Reverse Recovery Charge		-	4	-	nC
Dynamic Characteristics^b						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V},$ Frequency=1.0MHz	-	390	-	pF
C_{oss}	Output Capacitance		-	70	-	
C_{riss}	Reverse Transfer Capacitance		-	50	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-10\text{V}, R_L=10\Omega,$ $I_{DS}=-1\text{A}, V_{GEN}=-4.5\text{V},$ $R_G=6\Omega$	-	6	13	ns
T_r	Turn-on Rise Time		-	14	29	
$t_{d(OFF)}$	Turn-off Delay Time		-	28	55	
T_f	Turn-off Fall Time		-	20	39	
Gate Charge Characteristics^b						
Q_g	Total Gate Charge	$V_{DS}=-10\text{V}, V_{GS}=-4.5\text{V},$ $I_{DS}=-2.6\text{A}$	-	4.2	6	nC
Q_{gs}	Gate-Source Charge		-	0.6	-	
Q_{gd}	Gate-Drain Charge		-	1.3	-	
[SBD]						
V_R	Reverse Voltage	$I_R=0.5\text{A}$	20	-	-	V
V_{F1}	Forward Voltage	$I_F=500\text{mA}$	-	0.45	-	V
V_{F2}		$I_F=500\text{mA}, T_A=125^\circ\text{C}$	-	0.37	-	V
I_{R1}	Reverse Current	$V_R=10\text{V}$	-	2	10	μA
I_{R2}	Reverse Current	$V_R=20\text{V}$	-	10	40	μA
C^b	Junction Capacitance	$V_R=10\text{V},$ Frequency=1.0MHz	-	14	-	pF

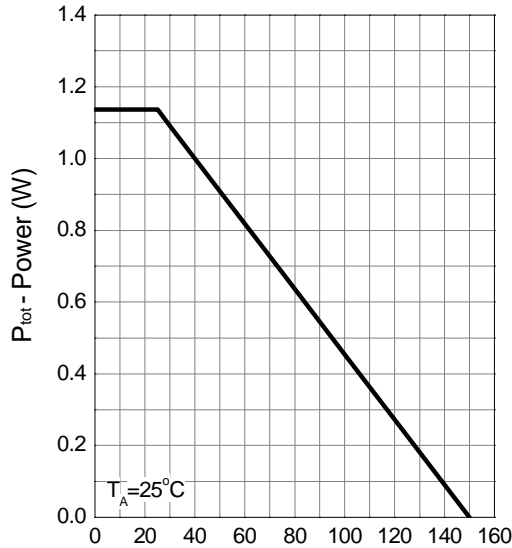
Note a : Pulse test ; pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

Note b : Guaranteed by design, not subject to production testing.

Typical Operating Characteristics (Cont.)

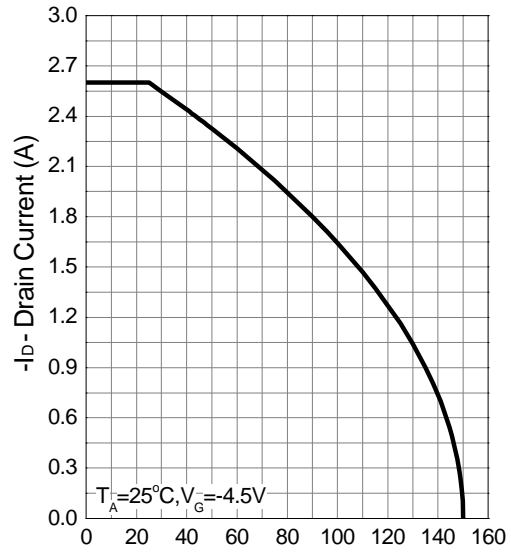
P-Channel

Power Dissipation



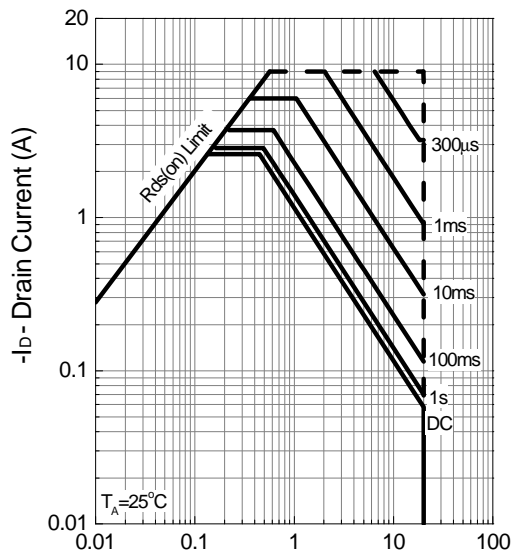
T_j - Junction Temperature (°C)

Drain Current



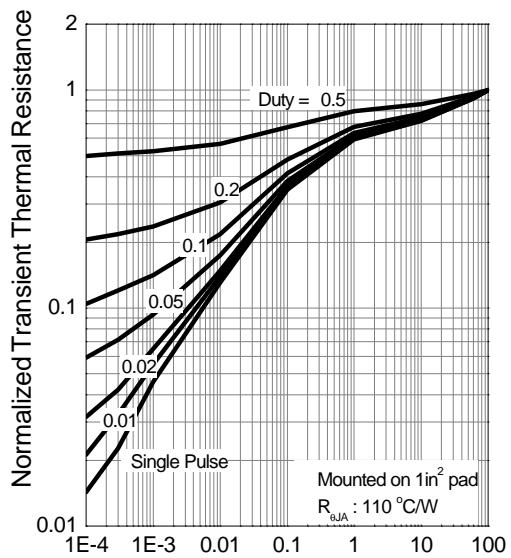
T_j - Junction Temperature (°C)

Safe Operation Area



-V_{DS} - Drain - Source Voltage (V)

Thermal Transient Impedance

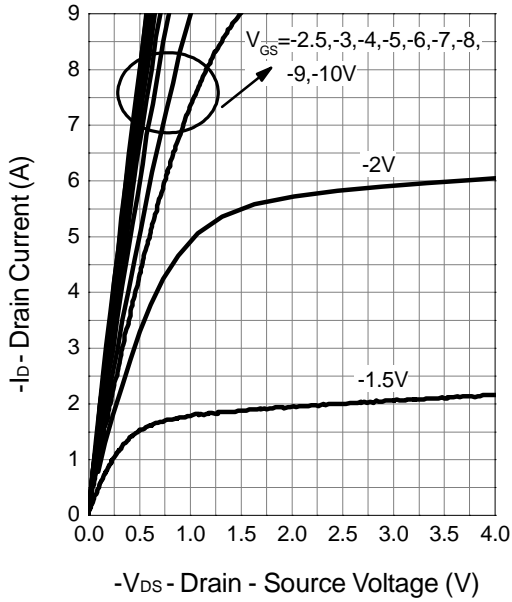


Square Wave Pulse Duration (sec)

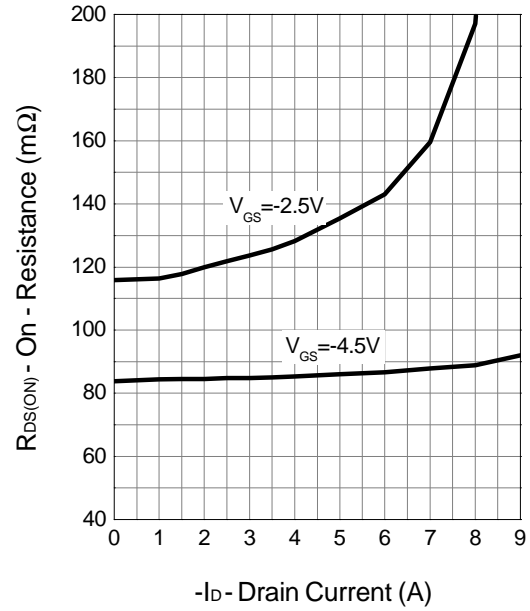
Typical Operating Characteristics (Cont.)

P-Channel

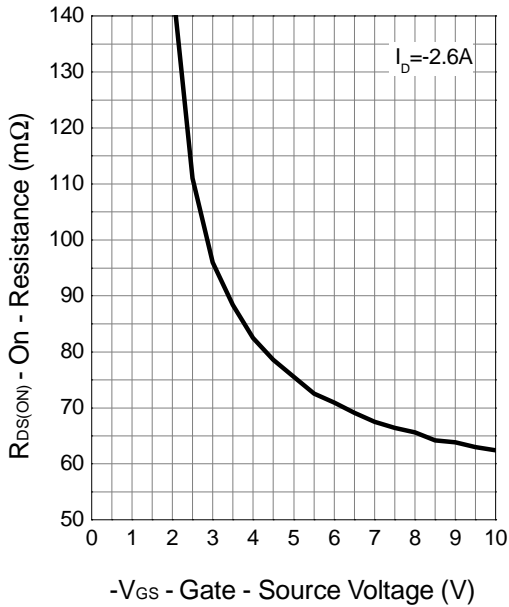
Output Characteristics



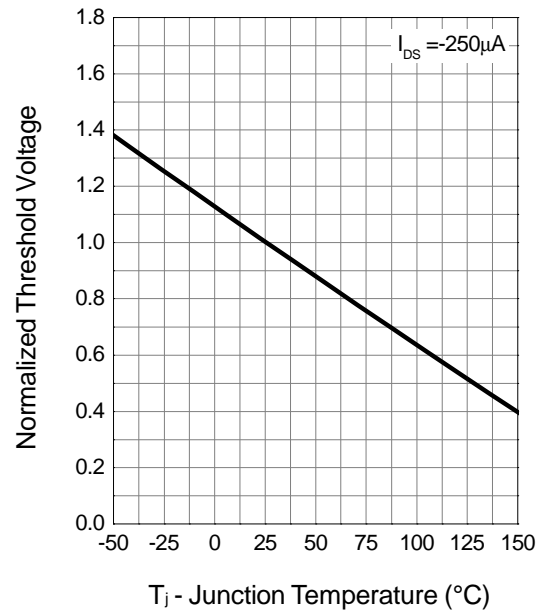
Drain-Source On Resistance



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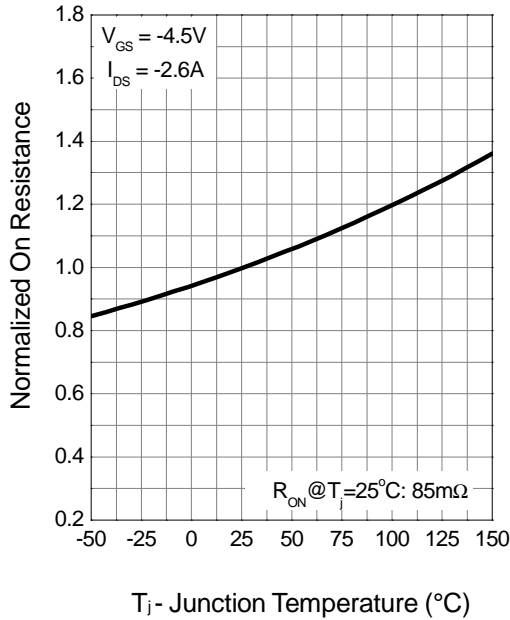
Gate Threshold Voltage



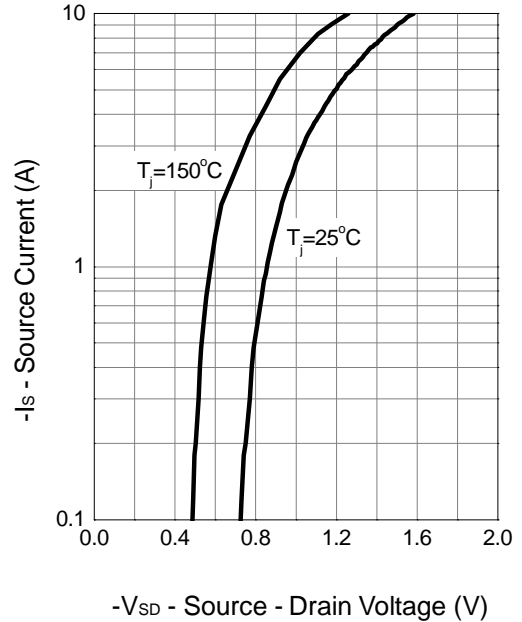
Typical Operating Characteristics (Cont.)

P-Channel

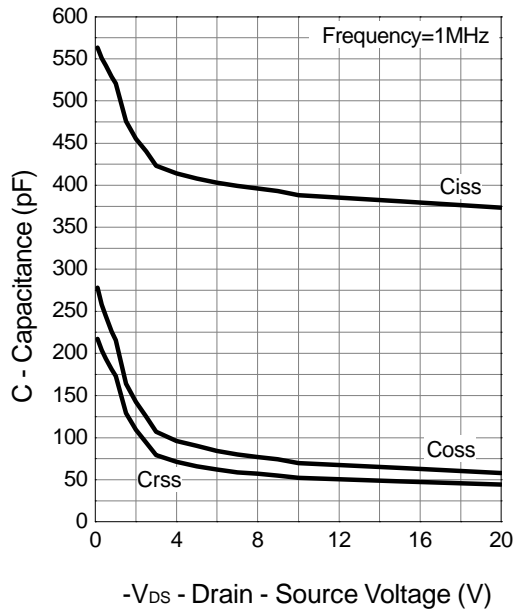
Drain-Source On Resistance



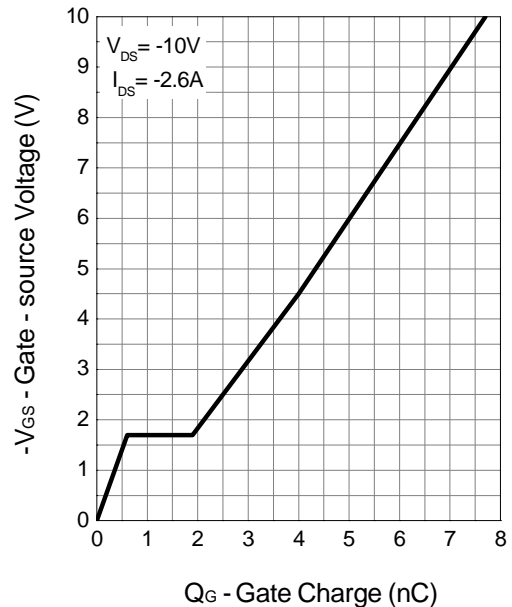
Source-Drain Diode Forward



Capacitance

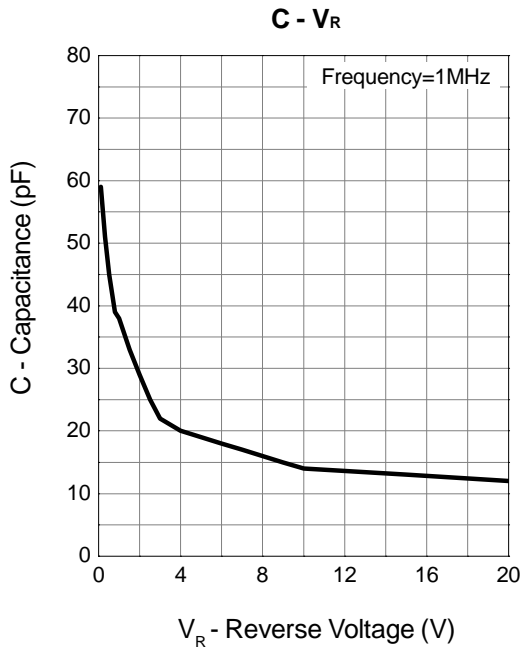
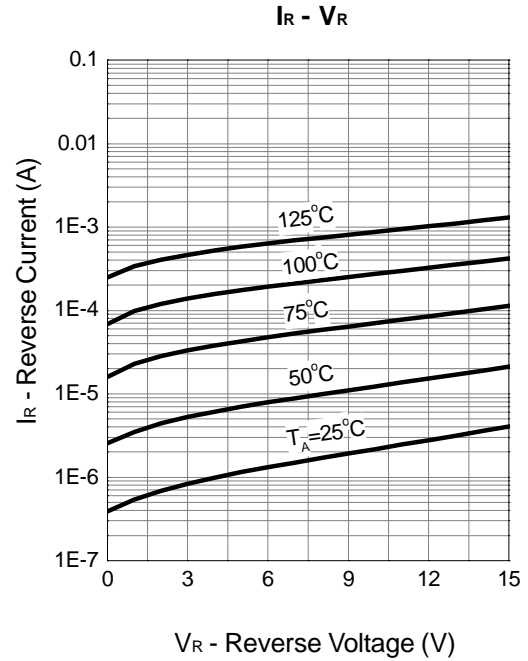
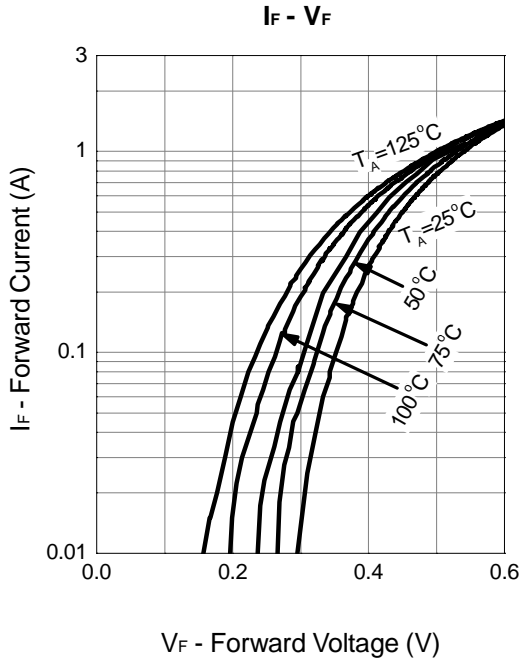


Gate Charge



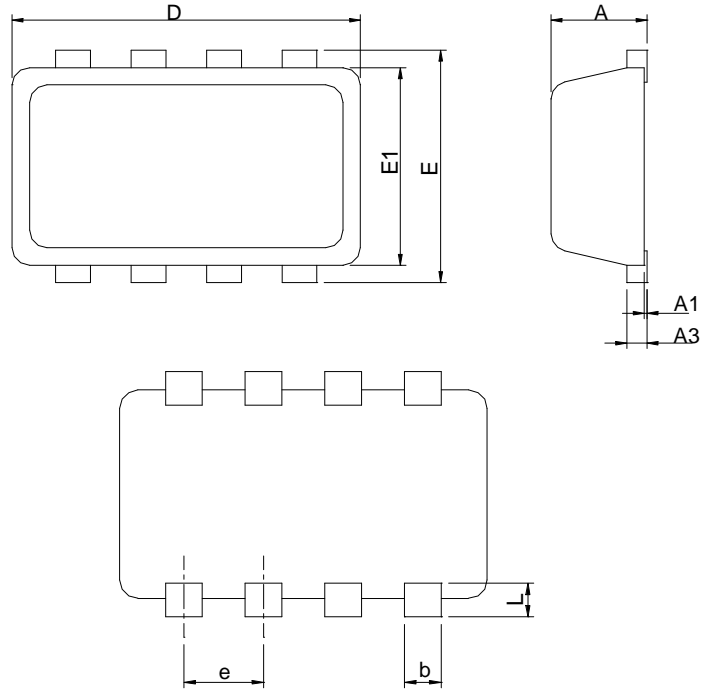
Typical Operating Characteristics (Cont.)

SBD



Package Information

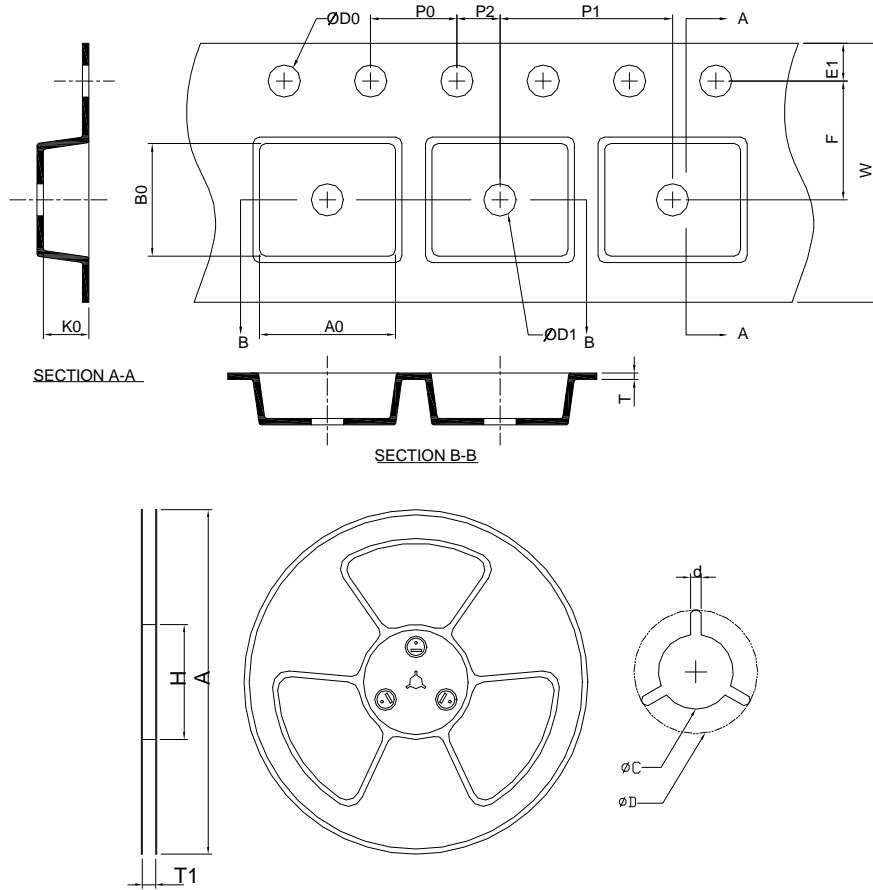
DFN3x2-8



SYMBOL	DFN3x2-8			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	0.80	1.00	0.031	0.039
A1	0.00	0.05	0.000	0.002
A3	0.08	0.25	0.003	0.010
b	0.24	0.35	0.009	0.014
D	2.90	3.10	0.114	0.122
E	1.90	2.10	0.075	0.083
E1	1.60	1.80	0.063	0.071
e	0.65 BSC		0.026 BSC	
L	0.20	0.40	0.008	0.016

Note : 1. Follow JEDEC MO-229 VECC.

Carrier Tape & Reel Dimensions



Application	A	H	T1	C	d	D	W	E1	F
DFN3x2-8	178.0 ±0.00	50 MIN.	12.4+2.00 -0.00	13.0+0.50 -0.20	1.5 MIN.	20.2 MIN.	12.0 ±0.30	1.75 ±0.10	5.5 ±0.05
	P0	P1	P2	D0	D1	T	A0	B0	K0
	4.0 ±0.10	8.0 ±0.10	2.0 ±0.05	1.5+0.10 -0.00	1.5 MIN.	0.6+0.00 -0.40	3.30 ±0.20	3.30 ±0.20	1.30 ±0.20

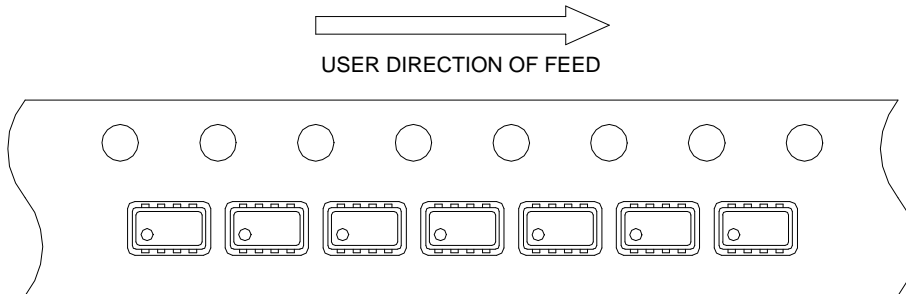
(mm)

Devices Per Unit

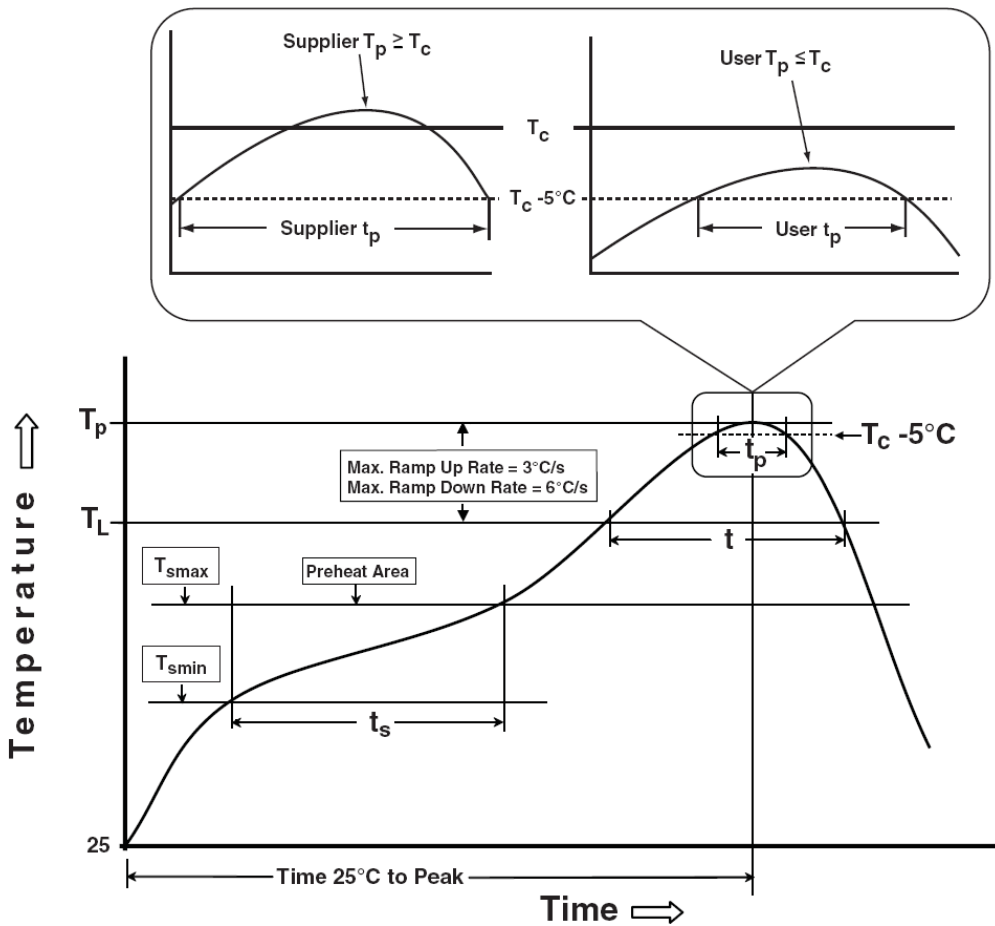
Package Type	Unit	Quantity
DFN3x2-8	Tape & Reel	3000

Taping Direction Information

DFN3x2-8



Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak		
Temperature min (T_{smin})	100 °C	150 °C
Temperature max (T_{smax})	150 °C	200 °C
Time (T_{smin} to T_{smax}) (t_s)	60-120 seconds	60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L)	183 °C	217 °C
Time at liquidous (t_L)	60-150 seconds	60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum.		
** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.		

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HOLT	JESD-22, A108	1000 Hrs, Bias @ 125°C
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C

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